

Supporting Information

© Copyright Wiley-VCH Verlag GmbH & Co. KGaA, 69451 Weinheim, 2006

Fine-Tuning of Relative Metal–Metal Distances within Highly Ordered Chiral 2D Nano-Patterns

Philipp Zell, Florian Mögele, Ulrich Ziener, Bernhard Rieger*

The following figures show results from STM measurements which are not presented in the publication as images but mentioned in the text.

Pd1

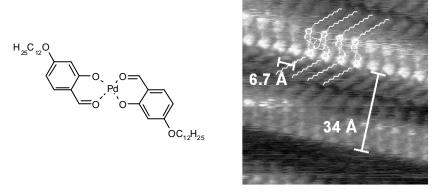


Image area: 7.8 x 7.8 nm², $V_{set} = -0.69$ V, $I_{set} = 14.6$ pA

Cu1

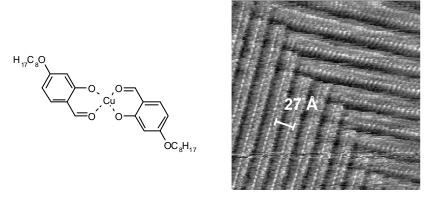


Image area: 25 x 25 nm², $V_{set} = -349$ mV, $I_{set} = 28.2$ pA

Cu3

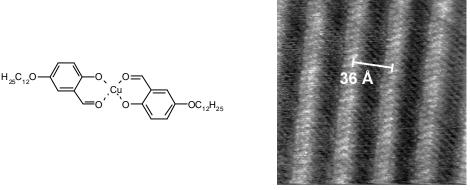


Image area: 19 x 19 nm², $V_{set} = -0.51$ V, $I_{set} = 24.4$ pA

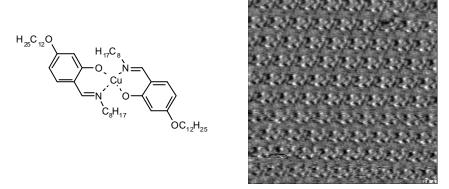


Image area: 15 x 15 nm², $V_{set} = -0.91$ V, $I_{set} = 31.0$ pA

Pd3

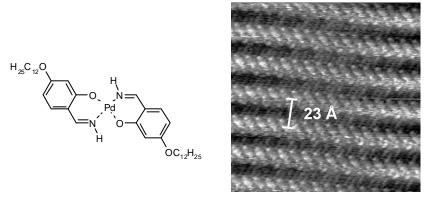


Image area: 15 x 15 nm², $V_{set} = -65$ mV, $I_{set} = 48.6$ pA